
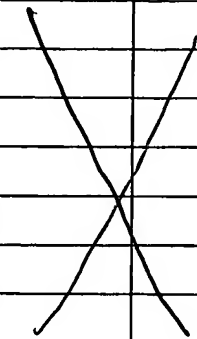
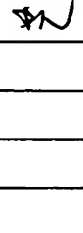
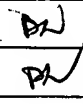
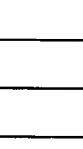


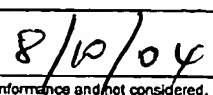


FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H-957-04		SERIAL NO.		
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT T. MATSUURA et al		GROUP		
				FILING DATE September 25, 2003				
U.S. PATENT DOCUMENTS								
* EXAMINER INITIAL	DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE <i>(If Appropriate)</i>		
	AA	5,026,669	06/25/91	Shinohara				
	AB	5,327,104	07/05/94	Kikushima				
	AC	5,731,231	03/24/98	Miyajima				
	AD	5,973,395	10/26/99	Suzuki et al				
	AE	6,208,020	03/27/01	Minamio et al				
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	AH							
	AI							
	AJ							
	AK							
FOREIGN PATENT DOCUMENTS								
	DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATIO YES NO		
	AL	11-195743	07/21/99	Japan		<input type="checkbox"/>	<input type="checkbox"/>	
	AM	2-240940	09/25/90	Japan		<input type="checkbox"/>	<input type="checkbox"/>	
	AN					<input type="checkbox"/>	<input type="checkbox"/>	
	AO					<input type="checkbox"/>	<input type="checkbox"/>	
	AP					<input type="checkbox"/>	<input type="checkbox"/>	
						<input type="checkbox"/>	<input type="checkbox"/>	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)								
	AR	"Semiconductor Assembling/Testing Technique of '99", Extra Issue of Monthly Semiconductor World, July 27, 1998.						
	AS							
	AT							
EXAMINER				DATE CONSIDERED				
								

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form next communication to applicant.